Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/025,797	KIM ET AL.	
Examiner	Art Unit	
Emmanuel Bayard	2638	

SEARCHED					
Class	Subclass	Date	Examiner		
375	144	145/05	26		
1	148	R			
	136				
1	143	V			
375	152	10/5/05	X/s		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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